

## **Application Data Sheet**

### **Application Information**

<b>Application Type::</b>	Regular
<b>Subject Matter::</b>	Utility
<b>CD-ROM or CD-R?::</b>	None
<b>Computer Readable Form (CRF)?::</b>	No
<b>Title::</b>	SUBSTRATE INSPECTING METHOD AND SUBSTRATE INSPECTING APPARATUS USING THE METHOD
<b>Attorney Docket Number::</b>	044499-0206
<b>Request for Early Publication?::</b>	No
<b>Request for Non-Publication?::</b>	No
<b>Suggested Drawing Figure::</b>	1
<b>Total Drawing Sheets::</b>	7
<b>Small Entity?::</b>	No
<b>Petition included?::</b>	No
<b>Secrecy Order in Parent Appl.?::</b>	No

### **Applicant Information**

<b>Applicant Authority Type::</b>	Inventor
<b>Primary Citizenship Country::</b>	Japan
<b>Status::</b>	Full Capacity
<b>Given Name::</b>	Kiyoshi
<b>Family Name::</b>	MURAKAMI
<b>City of Residence::</b>	Fukuchiyama-shi, Kyoto-fu
<b>Country of Residence::</b>	Japan

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**Country of mailing address::** Japan

### Correspondence Information

**Correspondence Customer Number::** 22428

**E-Mail address::** PTOMailWashington@Foley.com

### Representative Information

<b>Representative Customer Number::</b>	22428	
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### Domestic Priority Information

<b>Application::</b>	<b>Continuity Type::</b>	<b>Parent Application::</b>	<b>Parent Filing Date::</b>

### Foreign Priority Information

<b>Country::</b>	<b>Application number::</b>	<b>Filing Date::</b>	<b>Priority Claimed::</b>
Japan	JP-2003-050357	02/27/2003	Yes

### Assignee Information

**Assignee name::** Omron Corporation